## **CLAIMS**

## WHAT IS CLAIMED IS:

- 1. An optoelectronic device comprising:
- a multilayer semiconductor structure including an InP
- 3 substrate and an active region, the active region comprising at least a
- 4 hole quantum well layer of a semiconductor containing antimony and at
- 5 least one electron quantum well layer adjacent to the hole quantum well
- 6 layer which comprises a semiconductor containing nitrogen to provide a
- 7 type II quantum well structure.
- 1 2. The device of Claim 1 wherein the semiconductor
- 2 containing antimony is GaAsSb or InGaAsSb and the semiconductor
- 3 containing nitrogen is InAsN or InGaAsN.
- 1 3. The device of Claim 2 wherein there is an electron
- quantum well layer on each side of the hole quantum well layer and there
- 3 is a barrier layer adjacent to each electron quantum well layer on each
- 4 side of the hole quantum well layer to provide a conduction band profile
- for the active region having a W-shaped configuration.
- 1 4. The device of Claim 3 wherein the electron quantum
- well layers are in compressive strain and the hole quantum well layer is in
- 3 compressive strain.
- 5. The device of Claim 3 wherein the electron quantum
- well layers are in compressive strain and the hole quantum well layer is in
- 3 tensile strain.

- 1 6. The device of Claim 3 wherein the thickness of each
  2 electron quantum well layer and hole quantum well layer is between
  3 approximately 10 and 50 angstroms.
- 7. The device of Claim 3 wherein the barrier layers comprise GalnP.
- 1 8. The device of Claim 1 wherein the electron quantum
  2 well layers and hole quantum well layer form a first quantum well stage,
  3 and wherein the active region comprises a plurality of quantum well
  4 stages adjacent to each other each having electron quantum well layers
  5 surrounding a hole quantum well layer.
- 9. The device of Claim 8 including a barrier layer between each quantum well stage to provide a conduction band profile having a W-shaped configuration.
- 1 10. The device of claim 9 wherein the barrier layer between each quantum well stage comprises GalnP.
- 1 11. The device of Claim 1 including means for providing optical feedback to form an edge-emitting laser.
- 1 12. The device of Claim 1 including means for providing optical feedback to form a vertical cavity surface emitting laser.
- 13. The device of Claim 1 wherein the active region
   generates light having a wavelength greater than approximately 2 μm.
- 14. The device of Claim 1 wherein the active region
   generates light having a wavelength of approximately 3 μm.

- 15. The device of Claim 1 wherein the nitrogen content of the electron quantum well is 10% or less.
- 1 16. An optoelectronic device comprising:
- a multilayer semiconductor structure including an InP
- 3 substrate and an active region, the active region comprising at least a
- 4 hole quantum well layer of GaAsSb or InGaAsSb and an electron quantum
- well layer of InAsN or InGaAsN on each side of the hole quantum well
- 6 layer to provide a type II quantum well structure.
- 17. The device of Claim 16 wherein the electron quantum
- well layers are in compressive strain and the hole quantum well layer is in
- 3 compressive strain.
- 18. The device of Claim 16 wherein the thickness of each
- electron quantum well layer and hole quantum well layer is between
- 3 approximately 10 and 50 angstroms.
- 19. The device of Claim 16 including a barrier layer
- 2 adjacent to each electron quantum well layer to form a conduction band
- 3 profile having a W-shaped configuration.
- 1 20. The device of Claim 19 wherein the barrier layer
- 2 comprises GaInP.
- 1 21. The device of Claim 16 wherein the electron quantum
- 2 well layers and hole quantum well layer form a first quantum well stage,
- and wherein the active region comprises a plurality of quantum well
- 4 stages adjacent to each other.

- 22. The device of Claim 21 including a barrier layer of GalnP between each quantum well stage to form a conduction band profile having a W-shaped configuration.
- 1 23. The device of Claim 16 wherein the percentage of Ga 2 content of the electron quantum well layers is no more than 30%.
- 1 24. The device of Claim 16 including means for providing optical feedback to form an edge-emitting laser.
- 1 25. The device of Claim 16 including means for providing optical feedback to form a vertical cavity surface emitting laser.
  - 26. The device of Claim 16 wherein the nitrogen content of the electron quantum wells is 10% or less.
  - 27. An optoelectronic device comprising:
    - a multilayer semiconductor structure including an InP substrate and an active region, the active region comprising at least a hole quantum well layer of GaAsSb and a electron quantum well layer of InAsN on each side of the hole quantum well layer to provide a type II quantum well structure wherein the electron quantum well layers are in compressive strain and the hole quantum well layer is in compressive strain.
  - 28. The device of Claim 27 wherein the electron quantum well layers are lattice matched to InP.
- 29. The device of Claim 27 wherein the thickness of each electron quantum well layer and hole quantum well layer is between approximately 10 and 50 angstroms.

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- 30. The device of Claim 27 including a barrier layer adjacent to each electron quantum well layer to form a conduction band profile having a W-shaped configuration.
- 1 31. The device of Claim 30 wherein the barrier layers comprise GalnP.
- 32. The device of Claim 27 wherein the electron quantum well layers and hole quantum well layer form a first quantum well stage, and wherein the active region comprises a plurality of quantum well stages adjacent to each other.
- 33. The device of Claim 27 including a transitional layer of GalnP between each quantum well stage.
- 1 34. The device of Claim 27 including means for providing optical feedback to form an edge-emitting laser.
- 35. The device of Claim 27 including means for providing optical feedback to form a vertical cavity surface emitting laser.
- 36. The device of Claim 27 wherein the active region
   generates light having a wavelength greater than approximately 2 μm.
- $_1$  37. The device of Claim 27 wherein the active region generates light having a wavelength of approximately 3  $\mu m$ .
- 1 38. The device of Claim 27 wherein the nitrogen content 2 of the electron quantum wells is 10% or less.

- 1 39. A semiconductor laser comprising:
- 2 (a) a multilayer semiconductor structure including an InP
- 3 substrate and an active region, the active region comprising at least a
- 4 hole quantum well layer of a semiconductor containing antimony and at
- least one electron quantum well layer adjacent to the hole quantum well
- 6 layer which comprises a semiconductor containing nitrogen to provide a
- 7 type II quantum well structure; and
- 8 (b) means for providing optical feedback to provide lasing
- 9 action in the active region.
- 1 40. The laser of Claim 39 wherein there is an electron
- quantum well layer on each side of the hole quantum well layer and there
- 3 is a barrier layer adjacent to each electron quantum well layer on each
- 4 side of the hole quantum well layer to provide a conduction band profile
- for the active region having a W-shaped configuration.
- 1 41. The laser of Claim 40 wherein the semiconductor
- containing antimony is GaAsSb or InGaAsSb and the semiconductor
- 3 containing nitrogen is InAsN or InGaAsN.
- 1 42. The laser of Claim 40 wherein the electron quantum
- well layers are in compressive strain and the hole quantum well layer is in
- 3 compressive strain.
- 1 43. The laser of Claim 40 wherein the electron quantum
- well layers are in compressive strain and the hole quantum well layer is in
- 3 tensile strain.

- 1 44. The laser of Claim 40 wherein the thickness of each electron quantum well layer and hole quantum well layer is between
- 3 approximately 10 and 50 angstroms.
- 1 45. The laser of Claim 40 wherein the barrier layer comprises GaInP.
- 1 46. The laser of Claim 40 wherein the electron quantum
  2 well layers and hole quantum well layer form a first quantum well stage,
  3 and wherein the active region comprises a plurality of quantum well
  4 stages adjacent to each other each having electron quantum well layers
  5 surrounding a hole quantum well layer.
- 1 47. The laser of Claim 46 including a barrier layer of GalnP between each quantum well stage.
- 1 48. The laser of Claim 39 wherein the means for providing optical feedback forms an edge-emitting laser.
- 1 49. The laser of Claim 39 wherein the means for providing optical feedback forms a vertical cavity surface emitting laser.
- 50. The laser of Claim 39 wherein the active region
   generates light having a wavelength greater than approximately 2 μm.
- 51. The laser of Claim 39 wherein the active region
   generates light having a wavelength of approximately 3 μm.
- 1 52. The laser of Claim 39 wherein the nitrogen content of 2 the electron quantum wells is 10% or less.